

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Prior Application: S. NUMAZAWA et al
Serial No. 10/325,915
Filed: December 23, 2002

Group Art Unit 2825
Examiner: B. Keshavan
For: METHOD OF FABRICATING SEMICONDUCTOR
DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

February 25, 2004

Sir:

In accordance with the duty of disclosure, the Applicants inform the Examiner of the documents cited during prosecution of the parent application, USSN 10/325,915.

The Applicants request the Examiner to initial and return a copy of the attached PTO-1449 form as an indication that the references have been considered.

Respectfully submitted,



Daniel J. Stanger
Registration No. 32,846
Attorney for Applicants

MATTINGLY, STANGER & MALUR, P.C.
1800 Diagonal Road, Suite 370
Alexandria, Virginia 22314
Telephone: (703) 684-1120
Facsimile: (703) 684-1157
Date: February 25, 2004

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-710-06	SERIAL NO.		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT S. NUMAZAWA et al			
				FILING DATE 02/25/04		GROUP 2825	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AA	5,907,776	05/25/99	Hshieh et al			
	AB	5,918,114	06/29/99	Choi et al			
	AC	5,940,721	08/17/99	Kinzer et al			
	AD	6,117,734	09/2000	Nakamura			
	AE	5,783,491	07/1998	Nakamura			
	AF	5,479,037	12/1995	Hshich et al			
	AG	5,558,313	09/1996	Hshich et al			
	AH	5,578,508	11/1996	Baba et al			
	AI	5,981,344	11/1999	Hshich et al			
	AJ	5,072,266	12/1991	Bulucea et al			
	AK	5,283,201	02/1994	Tsang et al			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	666,590	08/09/95	Europe			<input type="checkbox"/> <input type="checkbox"/>
	AM	07-245400	09/19/95	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AN	04-017371	01/22/92	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AO	09-129877	05/16/97	Japan			<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
	AR						
	AS						
	AT						
EXAMINER				DATE CONSIDERED			
<small>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AA	5,366,914	11/1994	Takahashi et al			
	AB	5,298,442	03/1994	Bulucea et al			
	AC	5,763,915	06/1998	Hshich et al			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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	AM						<input type="checkbox"/> <input type="checkbox"/>
	AN						<input type="checkbox"/> <input type="checkbox"/>
	AO						<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
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